

Two New Papers on Josephson Tunnel Junctions with Ferromagnetic Interlayer

February 7, 2008 (H20). Josephson tunnel junctions with ferromagnetic interlayer are currently a subject of vivid interest and intense research. We like to attract our readers' attention to two new papers on this subject, which were recently submitted to *Phys. Rev. B* and are available as electronic preprints (the first paper is already accepted). Both studies involve SIFS (superconductor-insulator-ferromagnet-superconductor) junctions with the interlayer thickness $d_f \gg \xi_{f1}$, where ξ_{f1} is the decay length in the conducting ferromagnet.

The theoretical paper by Vasenko, Golubov, Kupriyanov and Weides investigates the SIFS junctions in the dirty limit using the quasi-classical theory and formulates a quantitative model describing the damped oscillations of critical current, I_c , as a function of thickness of the ferromagnetic layer. The negative sign of I_c corresponds to the so-called π state. The derived analytical expression for I_c was used by Vasenko *et al.* to fit recent experimental data and extract the parameters of F, where F was the $\text{Ni}_{0.6}\text{Cu}_{0.4}$ alloy. The example of such fit is shown in Figure 1.

The authors studied also the superconducting density of states (DOS) induced in F by the proximity effect. They showed that the oscillation pattern of DOS at the Fermi energy in F is nearly $\frac{1}{2}$ of the oscillation period of I_c . Therefore, the DOS oscillations do not reflect the 0 to π transition. The paper is accessible at [arXiv:0711.0365v1](https://arxiv.org/abs/0711.0365v1).

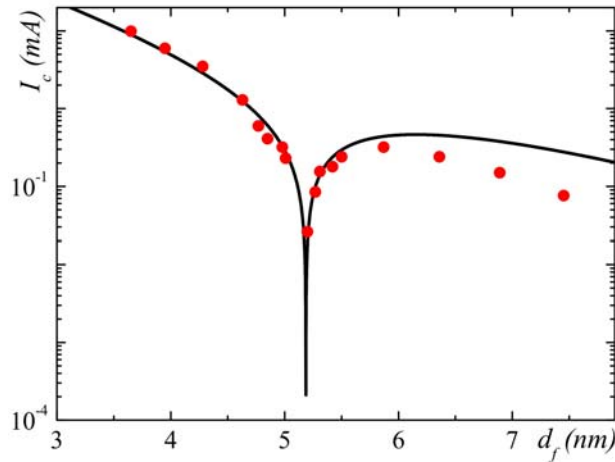


Fig. 1. Fit to the experimental data for the critical current I_c as function of F-layer thickness d_f in a Nb/ Al_2O_3 / $\text{Ni}_{0.6}\text{Cu}_{0.4}$ /Nb junction. The fitting parameters are the exchange field and the spin-flip scattering time in the ferromagnet.

The second paper by Pfeiffer *et al.* presents extensive experimental studies on the dynamic and static properties of 0-, π - and 0- π SIFS Josephson junctions of short and intermediate length (static properties of short 0- π junctions are also the subject of the Forum paper [ST27](#)). In the underdamped limit these junctions exhibit a rich dynamical behavior such as resonant steps on the current-voltage characteristics. Varying the experimental conditions, zero field steps, Fiske steps and Shapiro steps are observed with a high resolution.

A strong signature of the 0- π Josephson junction is demonstrated by measuring the critical current as a function of two components (B_x , B_y) of an in-plane magnetic

field, see Fig.2. The experimental observation of a *half-integer zero field step* in $0-\pi$ SIFS junctions is presented for the first time. The authors have observed *half-integer* Shapiro steps on the current-voltage characteristics of $0-$, $\pi-$ and $0-\pi$ Josephson junctions, which does not necessarily imply the presence of the second harmonic in the current-phase relation. The analysis of a short overdamped JJ in the framework of the RSJ model confirms this picture. The dynamic and static properties of $0-$ and $\pi-$ SIFS junctions are shown to be qualitatively similar to standard SIS junctions. The paper shows that SIFS $0-$, $\pi-$ and $0-\pi$ JJ technology can already be used to fabricate more complex superconducting electronic devices. The paper is available at <http://arxiv.org:80/abs/0801.3229v1>.

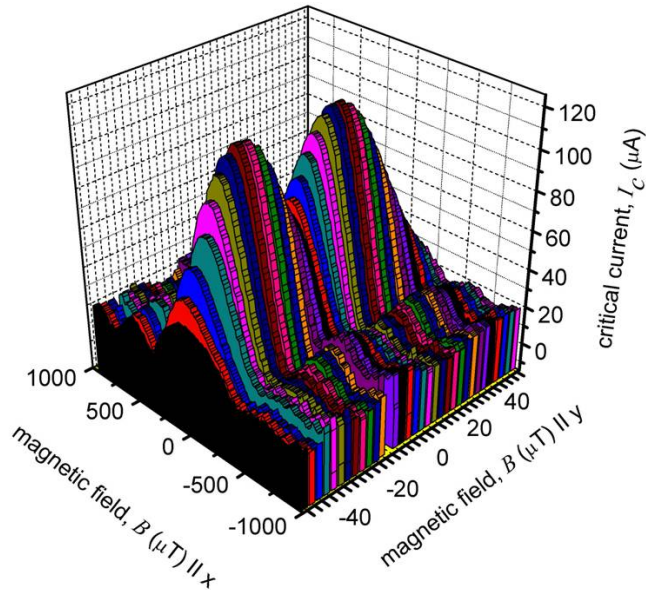


Fig. 2. Experimentally measured dependence of the critical current of a $0-\pi$ sample at $T=4.2$ K. For $B_y=0$, the critical current shows a regular Fraunhofer pattern. For $B_x=0$, a minimum around $B_y \sim 0$ is visible which is a characteristic feature of $0-\pi$ JJs.